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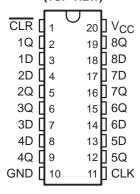
- **EPIC™** (Enhanced-Performance Implanted **CMOS) Process**
- Operating Range 2-V to 5.5-V V_{CC}
- Contain Eight Flip-Flops With Single-Rail **Outputs**
- **Direct Clear Input**
- Individual Data Input to Each Flip-Flop
- **Applications Include:**
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

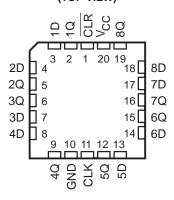
These circuits are positive-edge-triggered D-type flip-flops with a direct clear (CLR) input.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output.

SN54AHC273 . . . J OR W PACKAGE SN74AHC273 . . . DB, DGV, DW, N, OR PW PACKAGE (TOP VIEW)



SN54AHC273 . . . FK PACKAGE (TOP VIEW)



The SN54AHC273 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AHC273 is characterized for operation from -40°C to 85 °C.

FUNCTION TABLE (each flip-flop)

	INPUTS		OUTPUT
CLR	CLK	D	Q
L	X	Χ	L
Н	\uparrow	Н	Н
Н	\uparrow	L	L
Н	L	Χ	Q ₀

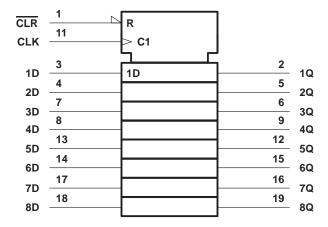


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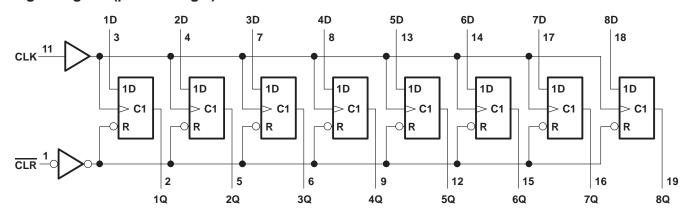


logic symbol†

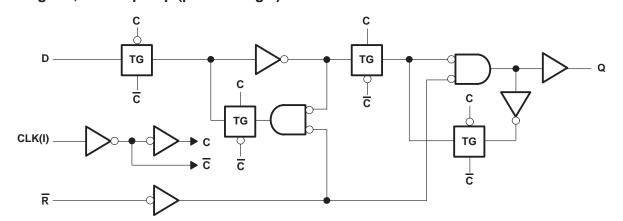


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



logic diagram, each flip-flop (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Output voltage range, VO (see Note 1)		$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$)		–20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CO}$	c)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	·····	±25 mA
Continuous current through V _{CC} or GND		
Package thermal impedance, θ _{JA} (see Note 2):		
5	DGV package	
	DW package	58°C/W
	N package	
	PW package	83°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

·			SN54A	HC273	SN74A	HC273	UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
V_{IH}	High-level input voltage	V _{CC} = 3 V	2.1		2.1		V
		V _{CC} = 5.5 V	3.85		3.85		1
		V _{CC} = 2 V		0.5		0.5	
V_{IL}	Low-level input voltage	V _{CC} = 3 V	0.9 0.9		V		
		V _{CC} = 5.5 V		1.65		1.65	1
٧ı	Input voltage	-	0	5.5	0	5.5	V
٧o	Output voltage		0	Vcc	0	Vcc	V
		V _{CC} = 2 V		-50		-50	μΑ
loh	High-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		-4		-4	
		$V_{CC} = 5 V \pm 0.5 V$		-8		-8	mA
		V _{CC} = 2 V		50		50	μΑ
I_{OL}	Low-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		4		4	A
		$V_{CC} = 5 V \pm 0.5 V$		8		8	mA
A # / A		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		100		100	
Δt/Δv	Input transition rise or fall rate $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$			20		20	ns/V
T _A	Operating free-air temperature	-	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T,	λ = 25°C	;	SN54AI	HC273	SN74AHC273		UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	1.9			1.9		1.9		
	I _{OH} = -50 μA	3 V	2.9			2.9		2.9		
Voн		4.5 V	4.4			4.4		4.4		V
	I _{OH} = -4 mA	3 V	2.58			2.48		2.48		
	I _{OH} = -8 mA	4.5 V	3.94			3.8		3.8		
		2 V			0.1		0.1		0.1	
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
V _{OL}		4.5 V			0.1		0.1		0.1	V
	I _{OL} = 4 mA	3 V			0.36		0.5		0.44	
	I _{OL} = 8 mA	4.5 V			0.36		0.5		0.44	
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40		40	μΑ
Ci	V _I = V _{CC} or GND	5 V		2.5	10				10	pF

 $^{^{\}star}$ On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0 V.

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

				SN54AHC273				SN74AHC273				
				25°C	AAINI AAAV		T _A = 25°C		MIN	MAN	UNIT	
			MIN	MAX	MIN	MAX	MIN	MIN MAX		MAX		
t Dulas duration	Pulse duration	CLR low	5		6		5		6		20	
t _W	Puise duration	CLK high or low	5		6.5		5		6.5		ns	
	Catum time	Data before CLK↑	5.5		6.5		5.5		6.5		20	
t _{su}	Setup time	CLR before CLK↑	2.5		2.5		2.5		2.5		ns	
th	Hold time, data after CLK↑		1.5		2		1		1		ns	

timing requirements over recommended operating free-air temperature range, $\rm V_{CC}$ = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

				SN54AHC273				SN74AHC273			
		Г		25°C	MIN MAX		T _A = 25°C		MIN	BAAV	UNIT
			MIN	MAX	MIN	WAX	MIN	MAX	IVIIIN	MAX	
t _w Pulse duration	CLR low	5		5		5		5			
t _W	Fulse duration	CLK high or low	5		5		5		5		ns
	Catum time	Data before CLK↑	4.5		4.5		4.5		4.5		ns
t _{su} S	Setup time	CLR before CLK↑	2		2		2		2		115
th	Hold time, data after CLK↑	•	1.5	·	2		1		1		ns



switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	TO LOAD		T _A = 25°C			HC273	SN74AI	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
f			C _L = 15 pF	75*	120*		65*		65		MHz	
f _{max}			C _L = 50 pF	50	75		45		45		IVITIZ	
t _{PHL}	CLR	Q	C _L = 15 pF		8.9*	13.6*	1*	16*	1	16	ns	
t _{PLH}	CLK		C: - 15 pF		8.7*	13.6*	1*	16*	1	16	20	
^t PHL	CLK	Q	C _L = 15 pF		8.7*	13.6*	1*	16*	1	16	ns	
t _{PHL}	CLR	Q	C _L = 50 pF		11.4	17.1	1	19.5	1	19.5	ns	
^t PLH	CLK	_	C 50 pF		11.2	17.1	1	19.5	1	19.5	no	
t _{PHL}	CLK	CLK	Q	C _L = 50 pF		11.2	17.1	1	19.5	1	19.5	ns
^t sk(o)			C _L = 50 pF			1.5**				1.5	ns	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

					-							
PARAMETER	FROM	то	LOAD	T,	T _A = 25°C		SN54AHC273		SN74AHC273		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
f			C _L = 15 pF	120*	165*		100*		100		MHz	
fmax			C _L = 50 pF	80	110		70		70		IVITIZ	
^t PHL	CLR	Q	C _L = 15 pF		5.2*	8.5*	1*	10*	1	10	ns	
^t PLH	CLK		C _I = 15 pF		5.8*	9*	1*	10.5*	1	10.5	ns	
t _{PHL}	CLK	Q	Q OL - 10 Pi	CL = 13 pr		5.8*	9*	1*	10.5*	1	10.5	115
^t PHL	CLR	Q	C _L = 50 pF		6.7	10.5	1	12	1	12	ns	
^t PLH	CLK		C: - 50 pF		7.3	11	1	12.5	1	12.5	ns	
t _{PHL}	CLK	CLK	Q	C _L = 50 pF		7.3	11	1	12.5	1	12.5	115
tsk(o)			C _L = 50 pF			1**				1	ns	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 5 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 4)

	PARAMETER			SN74AHC273			
	PARAMETER	MIN	TYP	MAX	UNIT		
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.7		V		
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.7		V		
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.7		V		
VIH(D)	High-level dynamic input voltage	3.5			V		
V _{IL(D)}	Low-level dynamic input voltage			1.5	V		

NOTE 4: Characteristics are for surface-mount packages only.

operating characteristics, T_A = 25°C

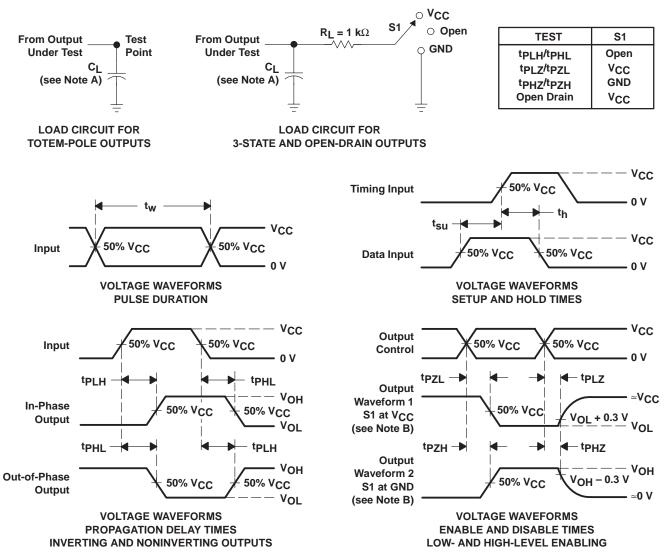
	PARAMETER	TEST C	ONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	31	pF



^{**} On products compliant to MIL-PRF-38535, this parameter does not apply.

^{**} On products compliant to MIL-PRF-38535, this parameter does not apply.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 3 \ ns$, $t_f \leq 3 \ ns$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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